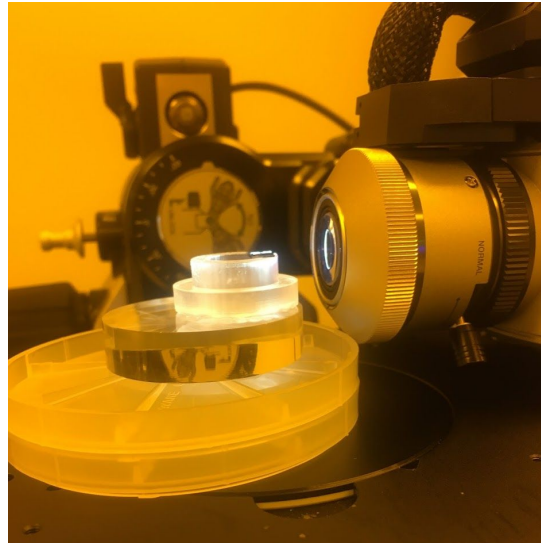


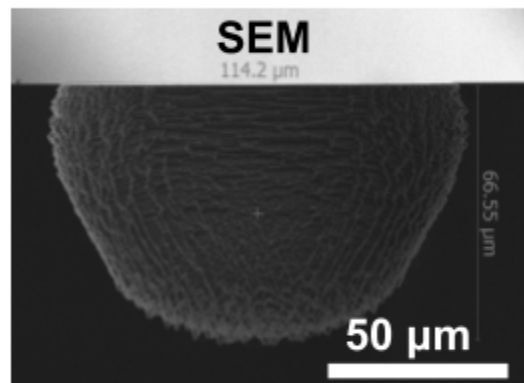
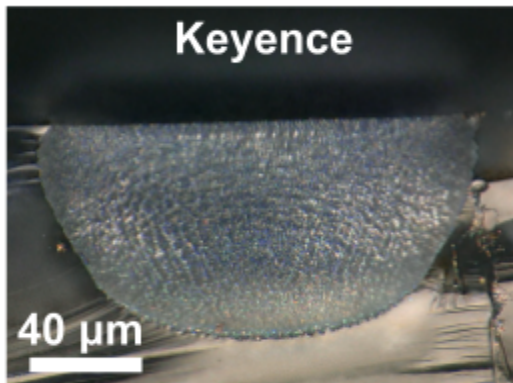
Keyence Imaging to Supplement SEM

We used the Keyence Digital microscope to image wafer pieces. This was to help us determine which samples we wanted to look at on the SEM and allows us to look at a larger number of

samples relatively quickly. It is cheaper than the SEM and can image a larger number of samples in the same amount of time.



The Keyence digital microscope is rotated 90degrees to take cross-sectional images cleaved wafer pieces. Acrylic blocks and wafer cases are used to hold the piece in front of the optics. Fine-tuning the height can be done with the stage, being mindful not to raise the stage into the optics.



Representative image of a cross-sectional image using the Keyence Digital Microscope (left) and SEM (right) on two different samples.